

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTY. DOCKET NO. *

SERIAL NO.

F070

09/840,558

APPLICANTS

Gerlach, van der Mast, and Scheinfein

FILING DATE

April 23, 2001

GROUP ART UNIT

2881

U.S. PATENT DOCUMENTS

*Examiner Initial	Cite No.	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date (if appropriate)
PB	A	4,126,781	11/21/78	Siegel	250	281	
PB	B	4,810,879	3/ 7/89	Walker	250	305	
PB	C	4,810,880	3/ 7/89	Gerlach	250	305	
PB	D	4,818,872	4/4/89	Parker et al.	250	309	
PB	E	5,834,770	11/10/98	Holkeboer et al.	250	281	
PB	F	6,218,664	4/17/01	Krans et al.	250	310	

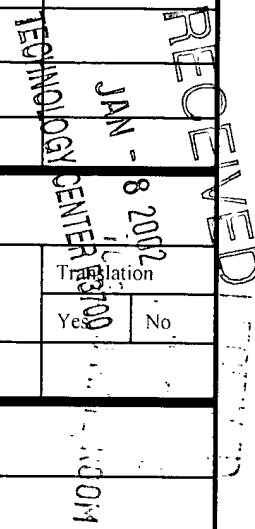
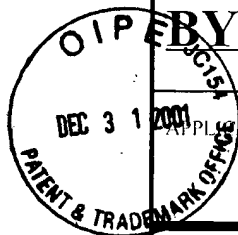
FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

Cite No.	Document Number	Date	Country	Class	Subclass	Translation
						Yes <input type="checkbox"/> No <input type="checkbox"/>

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

*Examiner Initial	Cite No.	
PB	H	BAUER, E., KOZIOL, C., LILIENKAMP, G., SCHMIDT, T.; "Spectromicroscopy in a Low Energy Electron Microscope", <u>Journal of Electron Spectroscopy and Related Phenomena</u> , Vol. 84, pp. 201-209(1997).
PB	I	KRANS, J.M. and van ROOY, T.L., "A Miniature Low Voltage SEM with High Resolution", <u>Microscopy and Microanalysis</u> , Vol 5, Supplement 2, pp 2-4, Portland, OR, Aug 1-5, 1999.
PB	J	KRUIT, P. "Auger Electron Spectroscopy in the STEM," <u>Quantitative Microbeam Analysis</u> , Proc. Of the 40 th Scottish Universities Summer School in Physics, August 1993.
PB	K	KRUIT, P., "Magnetic Through-the-lens Detection in Electron Microscopy and Spectroscopy, Part 1" <u>Advances in Optical and Electron Microscopy</u> , Vol. 12 ed., Mulvey and Sheppard, Academic Press, pp. 93-137 (1991).

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.





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*Examiner Initial	Cite No.	
Pb	L	POSTEK, MICHAEL T., "The Scanning Electron Microscope," <u>Handbook of Charged Particle Optics</u> , edited by Jon Orloff, CRC Press LLC, 1997; Ch. 9, pp.363-382.
Pb	M	PURCELL, E.M., "The Focusing of Charged Particles by a Spherical Condenser," <u>Phys. Rev.</u> , 54, pp. 818-826 (1938).
Pb	N	SAR-EL, H.Z., "Criterion for Comparing Analyzers," <u>The Review of Scientific Instruments</u> , Vol. 41, No. 4, 561-564 (1970).
EXAMINER	DATE CONSIDERED	
Paul Surgo	12/13/02	

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